

Title (en)
Off axis mirror alignment.

Title (de)
Ausrichtung eines verkippten Spiegels.

Title (fr)
Alignement d'un miroir désaxé.

Publication
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Application
EP 91121827 A 19911219

Priority
US 67601391 A 19910327

Abstract (en)
An apparatus and method are disclosed for increasing the alignment accuracy for off-axis mirrors in which a circular phase grating (14) is illuminated from behind onto the mirror (12) to be aligned creating a reflected image of the grating. The circular grating is aligned with the reflected image produced by the mirror so as to create an interference pattern when observed along an observation axis (16) which is an approximate mirror optical axis. The generated or observed interference pattern is observed for the presence of moire lines and the mirror is translated or rotated about the observation axis until moire lines are minimized in, or disappear from, the observed interference pattern. The observation axis is then aligned with the optical axis of the mirror which can be recorded or marked. In further embodiments of the invention, the fringe pattern is transferred, using one or more lenses (28), to an image processing element such as a camera (18). The image can be digitized and transferred to a process controller which is coupled to position translators connected to the mirror under test. The process controller analyzes the observed fringes and moves the mirror until a desired minimum number of moire lines are present. <IMAGE>

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IPC 8 full level
G02B 27/60 (2006.01); **G01B 11/27** (2006.01); **G02B 27/62** (2006.01)

CPC (source: EP US)
G01B 11/272 (2013.01 - EP US)

Citation (search report)
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JP H0593888 A 19930416; JP H0827444 B2 19960321

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